

Notice of References Cited	Application/Control No. 09/502,675		Applicant(s)/Patent Under Reexamination Yamazaki et al.	
	Examiner Evan T. Pert		Art Unit 2813	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
X	A	US-6,127,210	10-2000	Mimura et al.	--	--
X	B	US-5,706,064	01-1998	Fukunaga et al.	--	--
X	C	US-5,499,123	03-1996	Mikoshiba	--	--
X	D	US-5,302,966	04-1994	Stewart	--	--
	E	US-				
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	I	US-				
	J	US-				
	K	US-				
	L	US-				
	M	US-				

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N						
	O						
	P						
	Q						
	R						
	S						
	T						

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
X	U	Hatano et al. "A NOVEL Self-aligned Gate-overlapped LDD poly-Si TFT with High Reliability and Performance", 1997, IEEE, IEDM, pages 523-526.					
	V						
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	X						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.